

L8C201/202/203/204

512/1K/2K/4K x 9-bit Asynchronous FIFO

FEATURES

- ☐ First-In/First-Out (FIFO) using Dual-Port Memory
- Advanced CMOS Technology
- ☐ High Speed to 10 ns Access Time
- ☐ Asynchronous and Simultaneous Read and Write
- ☐ Fully Expandable by both Word Depth and/or Bit Width
- Empty and Full Warning Flags
- ☐ Half-Full Flag Capability
- ☐ Auto Retransmit Capability
- ☐ Package Styles Available:
 - 28-pin Plastic DIP
 - 32-pin Plastic LCC
 - 28-pin Ceramic Flatpack

DESCRIPTION

The L8C201, L8C202, L8C203, and L8C204 are dual-port First-In/First-Out (FIFO) memories. The FIFO memory products are organized as:

L8C201 — 512 x 9-bit L8C202 — 1024 x 9-bit L8C203 — 2048 x 9-bit

L8C204 — 4096 x 9-bit

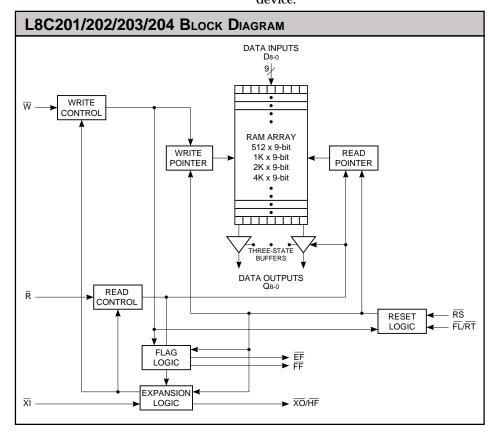
Each device utilizes a special algorithm that loads and empties data on a first-in/first-out basis. Full and Empty flags are provided to prevent data overflow and underflow. Three additional pins are also provided to allow for unlimited expansion in both word size and depth. Depth Expansion does not result in a flow-through penalty. Multiple devices are connected with the data and control signals in parallel. The active device is determined by the Expansion In (\overline{XI}) and Expansion Out (\overline{XO}) signals which are daisy chained from device to

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The read and write operations are internally sequential through the use of ring pointers. No address information is required to load and unload data. The write operation occurs when the Write $(\overline{\overline{W}})$ signal is LOW. Read occurs when Read (\overline{R}) goes LOW. The nine data outputs go to the high impedance state when R is HIGH. Retransmit (RT) capability allows for reset of the read pointer when RT is pulsed LOW, allowing for retransmission of data from the beginning. Read Enable (\overline{R}) and Write Enable (W) must both be HIGH during a retransmit cycle, and then \bar{R} is used to access the data. A Half-Full (HF) output flag is available in the single device and width expansion modes. In the depth expansion configuration, this pin provides the Expansion Out (\overline{XO}) information which is used to tell the next FIFO that it will be activated.

These FIFOs are designed to have the fastest data access possible. Even in lower cycle time applications, faster access time can eliminate timing bottlenecks as well as leave enough margin to allow the use of the devices without external bus drivers.

The FIFOs are designed for those applications requiring asychronous and simultaneous read/writes in multiprocessing and rate buffer applications.





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SIGNAL DEFINITIONS

Inputs

 \overline{RS} — Reset

Reset is accomplished whenever the Reset (\overline{RS}) input is taken to a LOW state. During reset, both internal read and write pointers are set to the first location. A reset is required after power-up before a write operation can take place. Both the Read Enable (\overline{R}) and Write Enable (\overline{W}) inputs must be in the HIGH state during the window shown (i.e., tWHSH before the rising edge of \overline{RS}) and should not change until tSHWL after the rising edge of \overline{RS} . Hall-Full Flag (\overline{HF}) will be reset to high after Reset (\overline{RS}).

\overline{W} — Write Enable

A write cycle is initiated on the falling edge of this input if the Full Flag (\overline{FF}) is not set. Data setup and hold time must be adhered to with respect to the rising edge of the Write Enable (\overline{W}) . Data is stored in the RAM array sequentially and independently of any on-going read operation.

To prevent data overflow, the Full Flag (\overline{FF}) will go LOW, inhibiting further write operations. Upon the completion of a valid read operation, the Full Flag (\overline{FF}) will go HIGH after tRHFH, allowing a valid write to begin. When the FIFO is full, the internal write pointer is blocked from \overline{W} , so external changes in \overline{W} will not affect the FIFO when it is full.

\overline{R} — Read Enable

A read cycle is initiated on the falling edge of the Read Enable (\overline{R}) provided the Empty Flag (\overline{EF}) is not set. The data is accessed on a First-In/First-Out basis, independent of any ongoing write operation. After Read Enable (\overline{R}) goes HIGH, the Data Outputs (D8-0) will return to a high impedance condition until the next read operation. When all the data has been read from the FIFO, the Empty Flag (\overline{EF}) will go LOW, allowing the

"final" read cycle but inhibiting further read operations with the data outputs remaining in a high impedance state. Once a valid write operating has been accomplished, the Empty Flag (\overline{EF}) will go HIGH after tWHEH and a valid read can then begin. When the FIFO is empty, the internal read pointer is blocked from \overline{R} so external changes in \overline{R} will not affect the FIFO.

$\overline{FL}/\overline{RT}$ — First Load/Retransmit

This is a dual-purpose input. In the Depth Expansion Mode, this pin is grounded to indicate that it is the first loaded (see Operating Modes). In the Single Device Mode, this pin acts as the retransmit input. The Single Device Mode is initiated by grounding the Expansion In (\overline{XI}) .

The FIFOs can be made to retransmit data when the Retransmit Enable control (RT) input is pulsed LOW. A retransmit operation will set the internal read pointer to the first location and will not affect the write pointer. Read Enable (\overline{R}) and Write Enable (\overline{W}) must be in the HIGH state during retransmit. This feature is useful when less than the full memory has been written between resets Retransmit will affect the Half-Full Flag (HF), depending on the relative locations of the read and write pointers. The retransmit feature is not compatible with the Depth Expansion Mode.

\overline{XI} — Expansion In

This input is a dual-purpose pin. Expansion In (\overline{XI}) is grounded to indicate an operation in the single device mode. Expansion In (\overline{XI}) is connected to Expansion Out (\overline{XO}) of the previous device in the Depth Expansion or Daisy Chain Mode.

D8-0 — Data Input

Data input signals for 9-bit wide data. Data has setup and hold time requirements with respect to the rising edge of \overline{W} .

Outputs

FF — Full Flag

The Full Flag ($\overline{\text{FF}}$) will go LOW, inhibiting further write operations, indicating that the device is full. If the read pointer is not moved after Reset ($\overline{\text{RS}}$), the Full Flag ($\overline{\text{FF}}$) will go LOW after 512 writes for the **L8C201**, 1024 writes for the **L8C202**, 2048 writes for the **L8C203**, and 4096 writes for the **L8C204**.

EF — Empty Flag

The Empty Flag (EF) will go LOW, inhibiting further read operations, when the read pointer is equal to the write pointer, indicating that the device is empty.

₹XO/HF — Expansion Out/Half-Full Flag

This is a dual-purpose output. In the Single Device Mode, when Expansion In (\overline{XI}) is grounded, this output acts as an indication of a half-full memory.

After half of the memory is filled and at the falling edge of the next write operation, the Half-Full Flag (\overline{HF}) will be set to LOW and will remain set until the difference between the write pointer and read pointer is less than or equal to one-half of the total memory of the device. The Half-Full Flag (\overline{HF}) is then deasserted by the rising edge of the read operation.

In the Depth Expansion Mode, Expansion In (\overline{XI}) is connected to Expansion Out (\overline{XO}) of the previous device. This output acts as a signal to the next device in the daisy chain by providing a pulse to the next device when the previous device reaches the last location of memory.

Q8-0 — Data Output

Data outputs for 9-bit wide data. This data is in a high impedance condition whenever Read Enable (\overline{R}) is in a HIGH state or the device is empty.



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OPERATING MODES

Single Device Mode

A single FIFO may be used when the application requirements are for the number of words in a single device. The FIFOs are in a Single Device Configuration when the Expansion In (\overline{XI}) control input is grounded. In this mode the Half-Full Flag (\overline{HF}) , which is an active-low output, is the active function of the combination pin $\overline{XO}/\overline{HF}$.

Width Expansion Mode

Word width may be increased simply by connecting the corresponding input control signals of multiple devices. Status flags (\overline{EF} , \overline{FF} , and \overline{HF}) can be detected from any one device. Any word width can be attained by adding additional FIFOs. Flag detection is accomplished by monitoring the \overline{FF} , \overline{EF} , and \overline{HF} signals on either (any) device used in the width expansion configuration. **Do not connect any output signals together.**

Depth Expansion (Daisy Chain) Mode

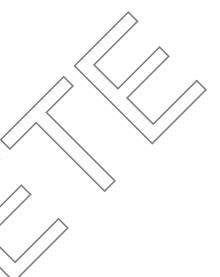
The FIFOs can easily be adapted to applications where the requirements are for greater than the number of words in a single device. Any depth can be attained by adding additional FIFOs. The FIFOs operates in the Depth Expansion configuration when the following conditions are met:

- The first device must be designated by grounding the First Load (FL) control input.
- 2. All other devices must have \(\overline{kL} \) in the HIGH state.
- 3. The Expansion Out (XO) pin of each device must be tied to the Expansion In (XI) pin of the next device with the last device connecting back to the first.

- 4. External logic is needed to generate a composite Full Flag (FF) and Empty Flag (EF). This requires the ORing of all EFs and ORing of all FFs (i.e., all must be set to generate the correct composite FF or EF).
- 5. The Retransmit (\overline{RT}) function and Half-Full Flag (\overline{HF}) are not available in the Depth Expansion Mode.

Bidirectional Mode

Applications which require data buffering between two systems (each system capable of read and write operations) can be achieved by pairing FIFOs. Care must be taken to assure that the appropriate flag is monitored by each system (i.e., \overline{FF} is monitored on the device when \overline{W} is used; \overline{EF} is monitored on the device when \overline{R} is used). Both Depth Expansion and Width Expansion may be used in this mode.





MAX	XIMUM RATINGS Above which useful life may be impaired (Notes 1, 2)	
	Storage temperature	–65°C to +150°C
	Operating ambient temperature	–55°C to +125°C
	Vcc supply voltage with respect to ground	−0.5 V to +7.0 V
	Input signal with respect to ground	−0.5 V to +7.0 V
	Signal applied to high impedance output	3.0 V to +7.0 V
	Output current into low outputs	25 mA

OPERATING CONDITIONS To meet spec	ified electrical and switching charact	reristics
Mode	Temperature Range (Ambient)	Supply Voltage
Active Operation, Commercial	0°C to +70°C	4,5 V ≤ V CC ≤ 5.5 V
Active Operation, Industrial	-40°C to +85°C	4,5 V ≤ V CC ≤ 5.5 V
Active Operation, Military	-55°C to +125°C	4.5 V ≤ V CC ≤ 5.5 V

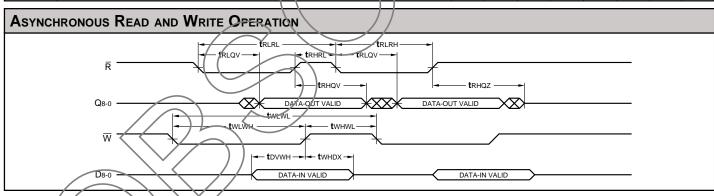
ELECTR	RICAL CHARACTERISTICS Ove	er Operating Conditions (Note 5)	\bigcirc			
			L8C20	1/202/2	03/204	
Symbol	Parameter	Test Condition	Min	Тур	Max	Unit
V OH	Output High Voltage	Vcc = 4.5 V, IoH = -2.0 mA	2.4			V
V OL	Output Low Voltage	Vcc = 4.5 V, IoL = 8.0 mA			0.4	V
V iH	Input High Voltage		2.0		V CC +0.3	V
V IL	Input Low Voltage	(Note 3)	-0.5		0.8	V
lix	Input Leakage Current	Ground ≤ ViN ≤ Vcc			±1	μΑ
loz	Output Leakage Current	R ≥ VIH, GND ≤ Vout ≤ Vcc			±10	μA
ICC2	Vcc Current, T/L Inactive	All Inputs = VIH MIN (Note 6)			15	mA
ICC3	Vcc Current, CMOS Standby	All Inputs = VCC (Note 12)			5	mA
CIN	Input Capacitance	Ambient Temp = 25°C, V cc = 4.5 V			5	pF
COUT	Output Capacitance	Test Frequency = 1 MHz (Note 9)			7	pF

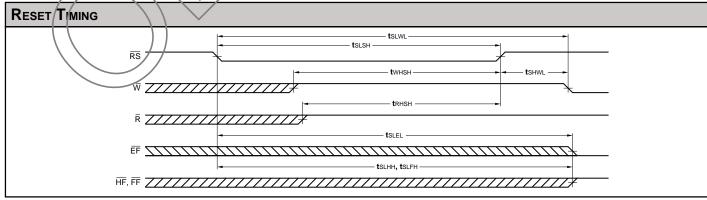
	L8C201/202/203/204-									
Symbol	Parameter	Test Condition	40	30	25	20	15	12	10	Unit
ICC1	Vcc Current, Active	(Note 5)	90	95	100	110	120	150	180	mA



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Async	HRONOUS AND RESET TIMING (ns)								
				L8C2	01/20	2/203	/204–		
		2	5	1	5	1	2	10	0
Symbol	Parameter	Min	Max	Min	Max	Min	Max	Min	Max
trlrl	Read Cycle Time (MHz)	35		25		20		15	
t RLQV	Read Low to Output Valid (Access Time)		25		15	_	12		10
t rhrl	Read High to Read Low (Notes 8, 9)	10		10	,	8		5	
t rlrh	Read Low to End of Read Cycle (Notes 8, 9)	25		15		12	^	10	
t rhqv	Read High to Output Valid	5		5		5 /		5	
t RHQZ	Read High to Output High Z (Note 14)		20		15	//	15	\wedge	15
twlwl	Write Cycle Time (Note 9)	35		25		20		1/5	
twlwh	Write Low to Write High (Notes 8, 9)	25		15		12	\vee	10	
twhwl	Write High to End of Write Cycle (Notes 8, 9)	10		10		8		5	
t DVWH	Data Valid to Write High (Notes 8, 9)	1/5		10		8		8	
t WHDX	Write High to Data Change (Notes 8, 9)	0	\wedge	0		0		0	
t SLSH	Reset Cycle Time (Notes 9, 10)	25/		15		12		10	
tslwl	Reset Low to Write Low (Notes 9, 10)	35		25		20		15	
twhsh	Write High to Reset High (Notes 9, 10)	25		15		12		10	
t rhsh	Read High to Reset High (Notes 9, 10)	25	Y /	15		12		10	
t SHWL	Reset High to Write Low (Notes 9, 10)	10		10		8		5	
tSLEL	Reset Low to Empty Flag Low		25		15		12		10
tslhh	Reset Low to Half-Full Flag High		25		15		12		10
tslfh	Reset Low to Full Flag High		25		15		12		10

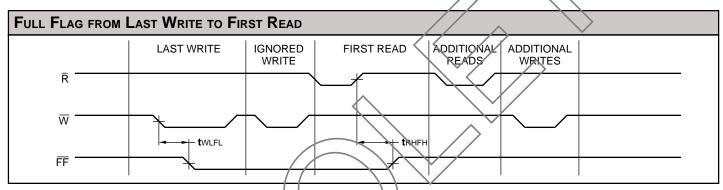


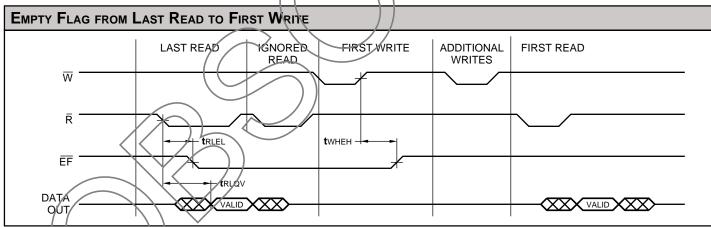


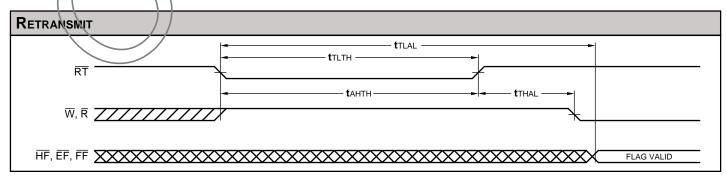


512/1K/2K/4K x 9-bit Asynchronous FIFO

FULL/E	MPTY FLAG AND RETRANSMIT TIMING (ns)								
				L8C2	01/20	2/203	/204–		
		2	5	1:	5	1	2	10	0
Symbol	Parameter	Min	Max	Min	Max	Min	Max	Min	Max
t rlqv	Read Low to Output Valid (Access Time)		25		15		12		10
t RLEL	Read Low to Empty Flag Low		25		15	_	12		10
t RHFH	Read High to Full Flag High		25		15		12		10
t WHEH	Write High to Empty Flag High		25		15		12		10
t WLFL	Write Low to Full Flag Low		25	4	15	/	1/2		10
t TLAL	Retransmit Cycle Time	35		25		20/		15)	
t TLTH	Retransmit Low to End of Retransmit Cycle (Notes 8, 9, 10)	25		15		12		1/0	
t AHTH	Read/Write High to Retransmit High (Notes 8, 9, 10)	25		15		12	Y /	10	
t THAL	Retransmit High to Read/Write Low (Note 9)	10		10		8		5	



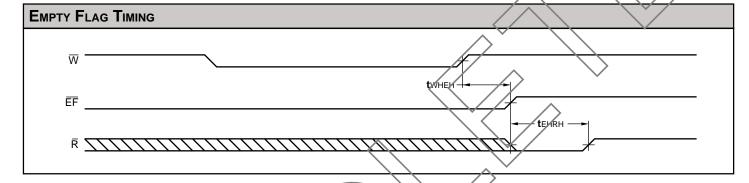


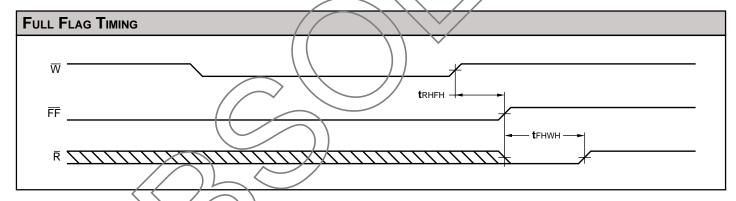


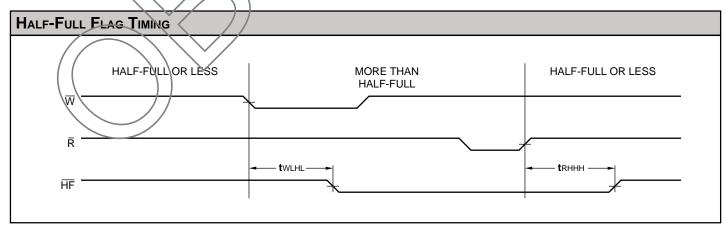


512/1K/2K/4K x 9-bit Asynchronous FIFO

FULL/H	FULL/HALF-FULL/EMPTY FLAG TIMING (ns)										
			L8C201/202/203/204-								
		2	5	1	5	1	2	1	0		
Symbol	Parameter	Min	Max	Min	Max	Min	Max	Min	Max		
t rhfh	Read High to Full Flag High		25		15		12		10		
t ehrh	Read Pulse Width After Empty Flag High	25		15		12		10			
t rhhh	Read High to Half-Full Flag High		25		15		12		10		
t WHEH	Write High to Empty Flag High		25		15		12		10		
t WLHL	Write Low to Half-Full Flag Low		25		15		1/2		10		
t FHWH	Write Pulse Width After Full Flag High (Note 9)	25		15		12/		10>			



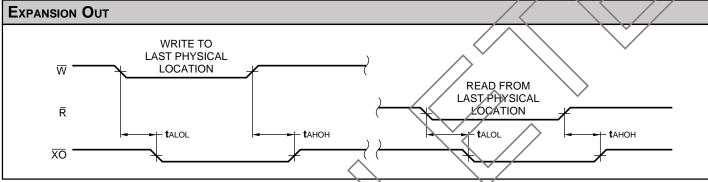


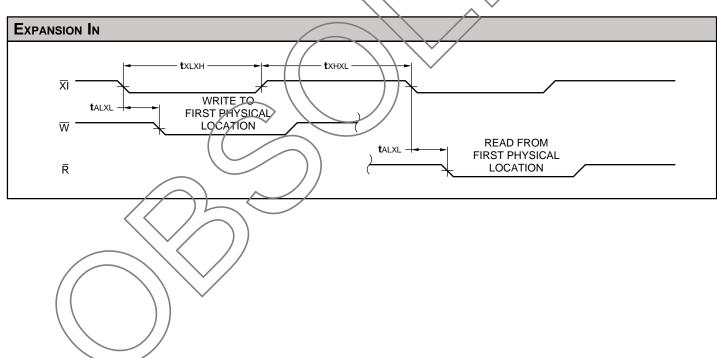




512/1K/2K/4K x 9-bit Asynchronous FIFO

EXPAN	SION TIMING (ns)										
			L8C201/202/203/204-								
		2	25 15 12 10						0		
Symbol	Parameter	Min	Max	Min	Max	Min	Max	Min	Max		
t alol	Read/Write to Expansion Out Low (Note 11)		25		15		12		12		
t AHOH	Read/Write to Expansion Out High (Note 11)		25		15	_	12		12		
t XLXH	Expansion In Pulse Width (Notes 9, 11)	25		15		12		10			
t XHXL	Expansion In High to Expansion In Low (Notes 9, 11)	10		10		10	\wedge	10			
t alxl	Read/Write Low to Expansion In Low (Notes 9, 11)	15		12	\langle	8		8			



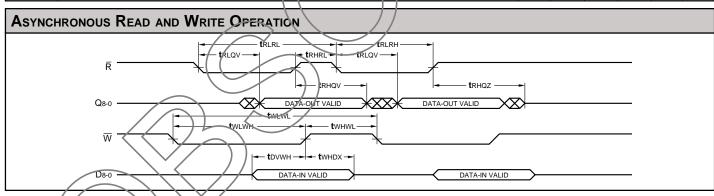


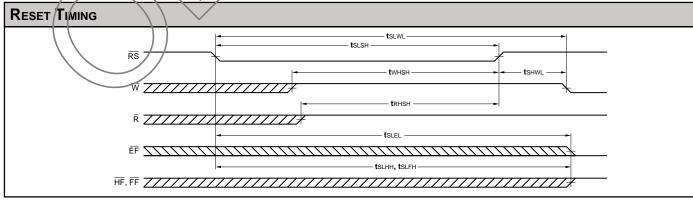


512/1K/2K/4K x 9-bit Asynchronous FIFO

SWITCHING CHARACTERISTICS Over Military Operating Range

Asynci	HRONOUS AND RESET TIMING (ns)						
			L8C2	01/20	2/203/	/204–	
		4	0	3	0	2	0
Symbol	Parameter	Min	Max	Min	Max	Min	Max
trlrl	Read Cycle Time (MHz)	50		40		30	
t rlqv	Read Low to Output Valid (Access Time)		40		30		20
t rhrl	Read High to Read Low (Notes 8, 9)	10		10		10	
t rlrh	Read Low to End of Read Cycle (Notes 8, 9)	40		30	^	20	
t rhqv	Read High to Output Valid	5	< <	5		5	
t RHQZ	Read High to Output High Z (Note 14)		25	V /	20	\wedge	15
twlwl	Write Cycle Time (Note 9)	50		40		30	
twlwh	Write Low to Write High (Notes 8, 9)	40		30	Y /	20	
twhwl	Write High to End of Write Cycle (Notes 8, 9)	10		10		10	
t DVWH	Data Valid to Write High (Notes 8, 9)	20		18		12	
twhox	Write High to Data Change (Notes 8, 9)	0		0		0	
tslsh	Reset Cycle Time (Notes 9, 10)	40		30		20	
tslwl	Reset Low to Write Low (Notes 9, 10)	50>		40		30	
twhsh	Write High to Reset High (Notes 9, 10)	/40		30		20	
t RHSH	Read High to Reset High (Notes 9, 10)	40		30		20	
t SHWL	Reset High to Write Low (Notes 9, 10)	10		10		10	
tSLEL	Reset Low to Empty Flag Low		50		40		30
tslhh	Reset Low to Half-Full Flag High		50		40		30
t SLFH	Reset Low to Full Flag High		50		40		30



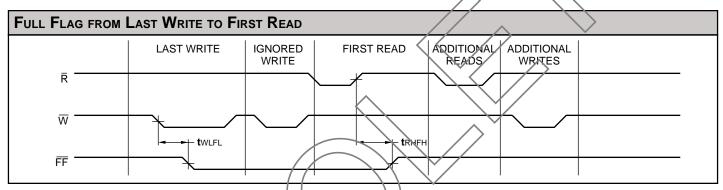


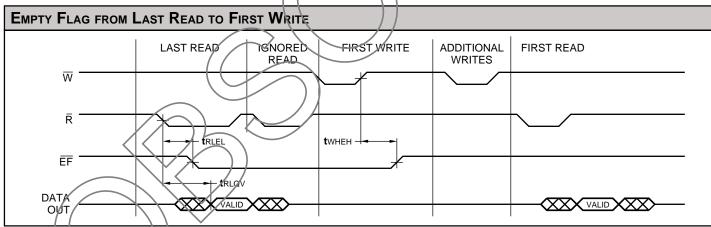


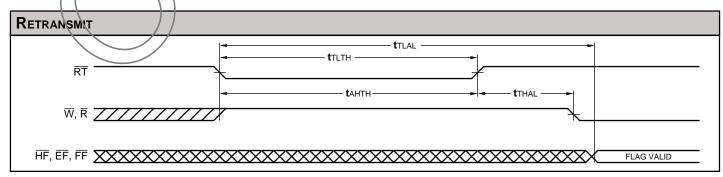
512/1K/2K/4K x 9-bit Asynchronous FIFO

SWITCHING CHARACTERISTICS Over Military Operating Range

FULL/E	MPTY FLAG AND RETRANSMIT TIMING (ns)								
		L8C201/202/203/204-							
		40 30 20					0		
Symbol	Parameter	Min	Max	Min	Max	Min	Max		
t rlqv	Read Low to Output Valid (Access Time)		40		30		20		
t RLEL	Read Low to Empty Flag Low		30		30		20		
t RHFH	Read High to Full Flag High		35		30		20		
twheh	Write High to Empty Flag High		35		30		20		
tWLFL	Write Low to Full Flag Low		35		30		20		
t TLAL	Retransmit Cycle Time	50		40		30	>		
t TLTH	Retransmit Low to End of Retransmit Cycle (Notes 8, 9, 10)	40		30		20			
t ahth	Read/Write High to Retransmit High (Notes 8, 9, 10)	40		30	Y /	20			
t THAL	Retransmit High to Read/Write Low (Note 9)	10		10		10			





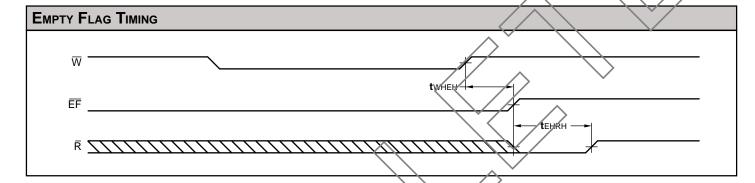


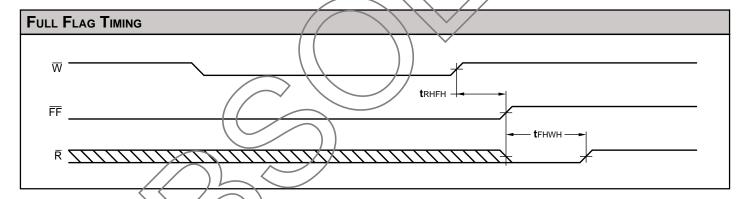


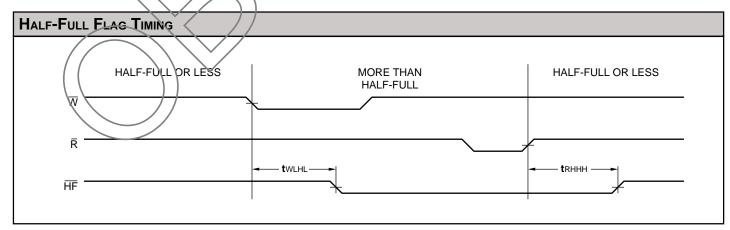
512/1K/2K/4K x 9-bit Asynchronous FIFO

SWITCHING CHARACTERISTICS Over Military Operating Range

FULL/H	ALF-FULL/EMPTY FLAG TIMING (ns)									
			L8C201/202/203/204-							
		40	40 30 20							
Symbol	Parameter	Min	Max	Min	Max	Min	Max			
t RHFH	Read High to Full Flag High		35		30		20			
t ehrh	Read Pulse Width After Empty Flag High	40		30		20				
t RHHH	Read High to Half-Full Flag High		50		40		30			
t wheh	Write High to Empty Flag High		35		30		20			
t WLHL	Write Low to Half-Full Flag Low		50		40		30			
t FHWH	Write Pulse Width After Full Flag High (Note 9)	10		30/		20	>			







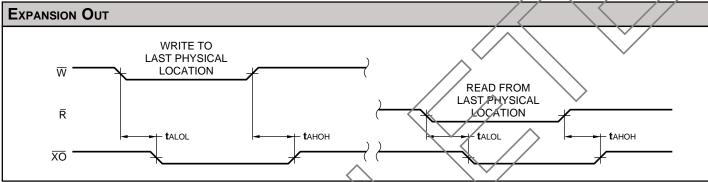
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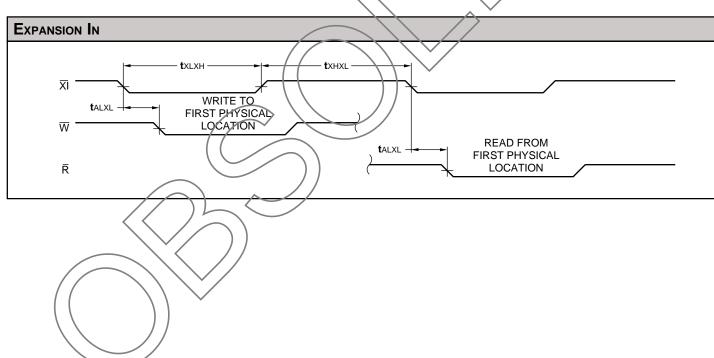


512/1K/2K/4K x 9-bit Asynchronous FIFO

SWITCHING CHARACTERISTICS Over Military Operating Range

EXPAN	Expansion Timing (ns)										
	L8C20										
		4	0	3	0	20	0				
Symbol	Parameter	Min	Max	Min	Max	Min	Max				
t alol	Read/Write to Expansion Out Low (Note 11)		40		30		20				
t AHOH	Read/Write to Expansion Out High (Note 11)		40		30		20				
txlxh	Expansion In Pulse Width (Notes 9, 11)	40		30		20					
t XHXL	Expansion In High to Expansion In Low (Notes 9, 11)	10		10	^	10					
t ALXL	Read/Write Low to Expansion In Low (Notes 9, 11)	10 -		10		10					





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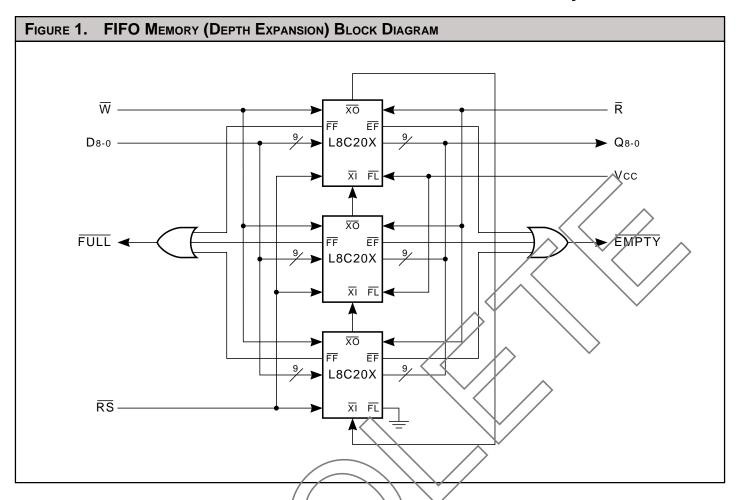


TABLE 1. RESET AND RETRANSMIT (SINGLE DEVICE CONFIGURATION/WIDTH EXPANSION MODE)										
	INTERNAL STATUS				OUTPUTS					
MODE	RS RT XI	Read Pointer	Write Pointer	EF	FF	HF				
Reset	0 X 0	Location Zero	Location Zero	0	1	1				
Retransmit	1 0 0	Location Zero	Unchanged	Х	Х	X				
Read/Write	1 1 0	Increment	Increment	Х	Х	Х				

TABLE 2 RESET AND FIRST LOAD TRUTH TABLE (DEPTH EXPANSION/COMPOUND EXPANSION MODE)											
	//	INPUTS		INTERNAL STATUS		OUTPUTS					
MODE	R\$	RT	ΧĪ	Read Pointer	Write Pointer	EF	FF				
Reset First Device	9/	0	(1)	Location Zero	Location Zero	0	1				
Reset All Others	9/	1	(1)	Location Zero Disabled	Location Zero Disabled	0	1				
Read/Write	1	(2)	(1)	X	X	X	X				

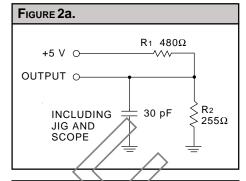
- (1) See Figure 1 (Depth Expansion Block Diagram)
- (2) Unchanged

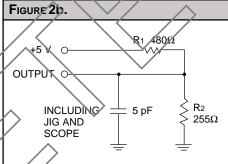
512/1K/2K/4K x 9-bit Asynchronous FIFO

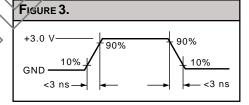
NOTES

- 1. Maximum Ratings indicate stress specifications only. Functional operation of these products at values beyond those indicated in the Operating Conditions table is not implied. Exposure to maximum rating conditions for extended periods may affect reliability of the tested device.
- 2. The products described by this specification include internal circuitry designed to protect the chip from damaging substrate injection currents and accumulations of static charge. Nevertheless, conventional precautions should be observed during storage, handling, and use of these circuits in order to avoid exposure to excessive electrical stress values.
- 3. This product provides hard clamping of transient undershoot. Input levels below ground will be clamped beginning at $-0.6\ V.$ A current in excess of 100 mA is required to reach $-2\ V.$ The device can withstand indefinite operation with inputs as low as $-3\ V$ subject only to power dissipation and bond wire fusing constraints.
- 4. "Typical" supply current values are not shown but may be approximated. At a VCC of +5.0 V, an ambient temperature of +25°C and with nominal manufacturing parameters, the operating supply currents will be approximately 3/4 or less of the maximum values shown.
- 5. Tested with outputs open and data inputs changing at the specified read and write cycle rate. The device is neither full or empty for the test.
- 6. Tested with outputs open in the worst static input control signal combination (i.e., W, R, XI, FL, and RS).
- 7. These parameters are guaranteed but not 100% tested.
- 8. Test conditions assume input transition times of 5 ns or less, reference levels of 1.5 V output loading for specified 10½ and IO½ plus 30 pF (Fig. 2a), and input pulse levels of 0 to 3.0 V (Fig. 3).
- 9. Each parameter is shown as a minimum or maximum value. Input requirements are specified from the point of view of the external system driving the chip. For example, trlr is specified as a minimum since the external system must supply at least that much time to meet the worst-case require-

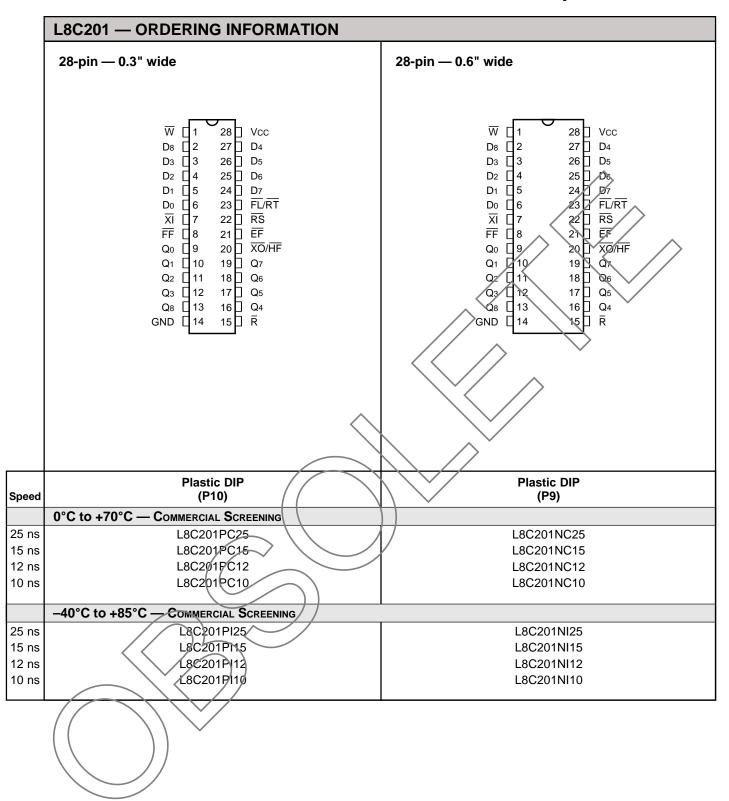
- ments of all parts. Responses from the internal circuitry are specified from the point of view of the device. Access time, for example, is specified as a maximum since worst-case operation of any device always provides data within that time.
- 10. When cascading devices, the reset pulse width must be increased to equal $t_{SLSH} + t_{SLHH}$.
- 11. It is not recommended that Logic Devices and other vendor parts be cascaded together. The parts are designed to be pinfor-pin compatible but temperature and voltage compensation may vary from vendor to vendor. Logic Devices can only guarantee the cascading of Logic Devices parts to other Logic Devices parts.
- 12. Tested with output open and $\overline{RS} = \overline{FL}$ = $\overline{XI} = \overline{R} = \overline{W} = VCC$.
- 13. At any given temperature and voltage condition, output disable time is less than output enable time for any given device.
- 14. Transition is measured ± 200 mV from steady state voltage with specified loading in Fig. 2b. This parameter is sampled and not 100% tested.
- 15. This product is a very high speed device and care must be taken during testing in order to realize valid test information. Inadequate attention to setups and procedures can cause a good part to be rejected as faulty. Long high-inductance leads that cause supply bounce must be avoided by bringing the VCC and ground planes directly up to the contactor fingers. A 0.91 μ F high frequency capacitor is also required between VCC and ground. To avoid signal reflections, proper terminations must be used.



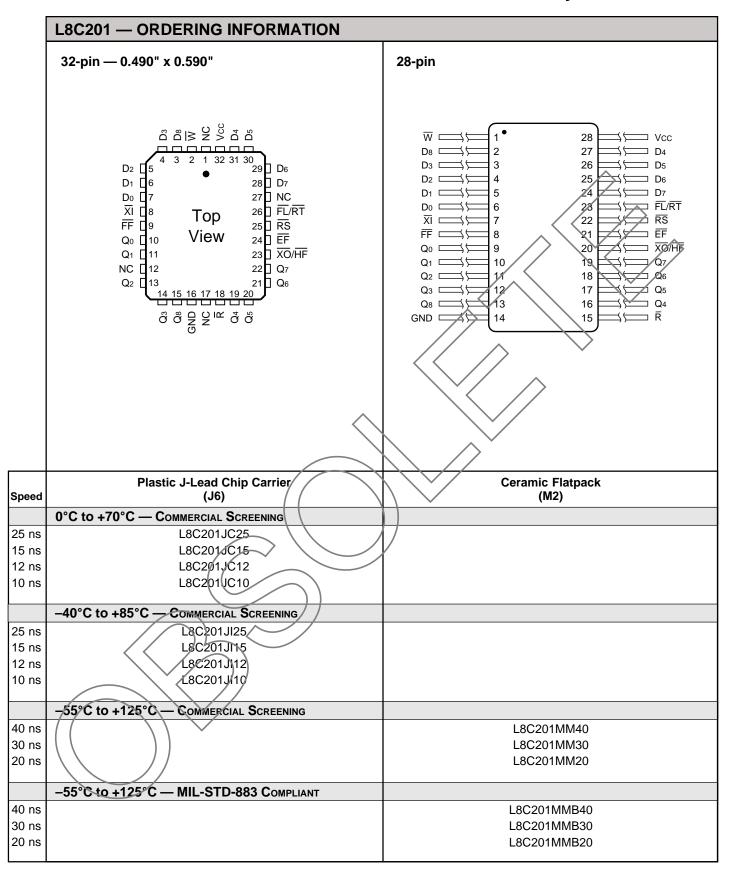




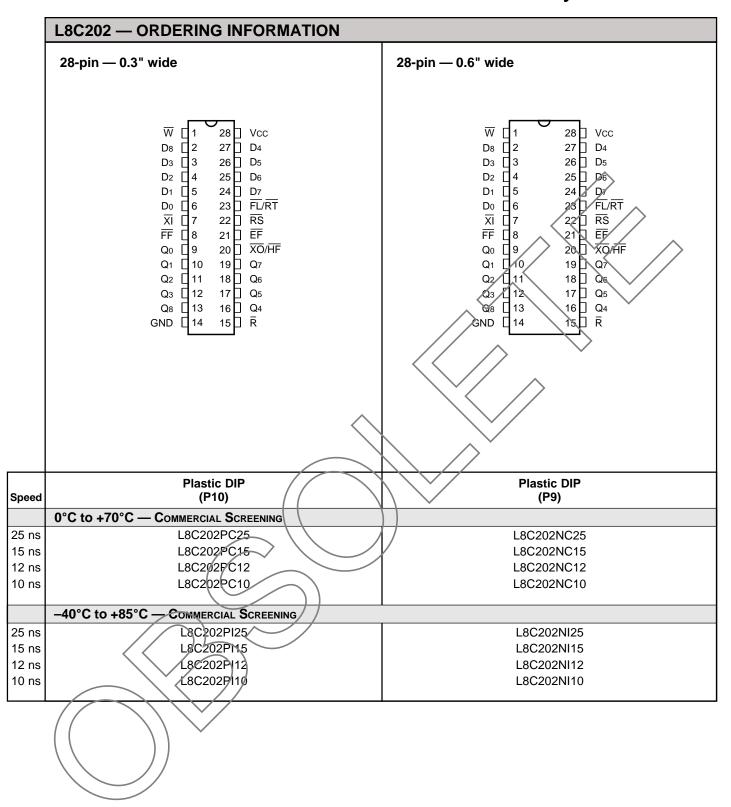




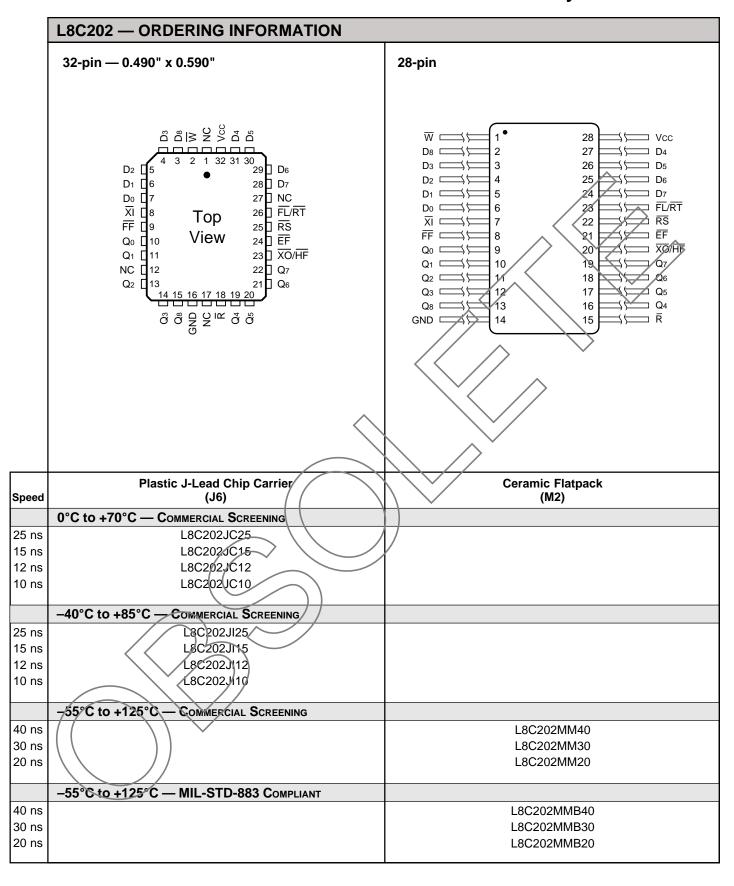




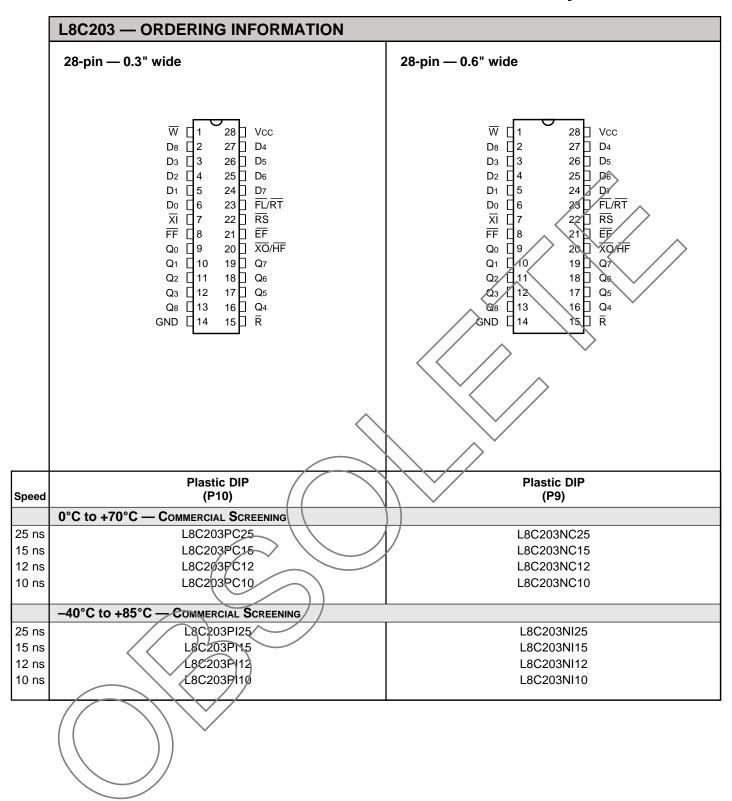




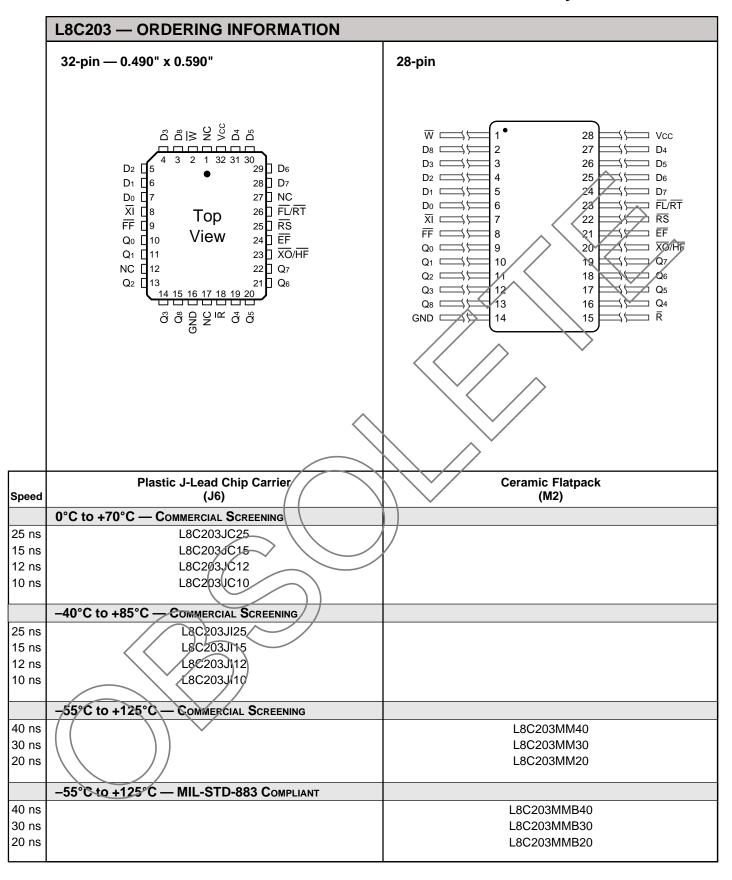






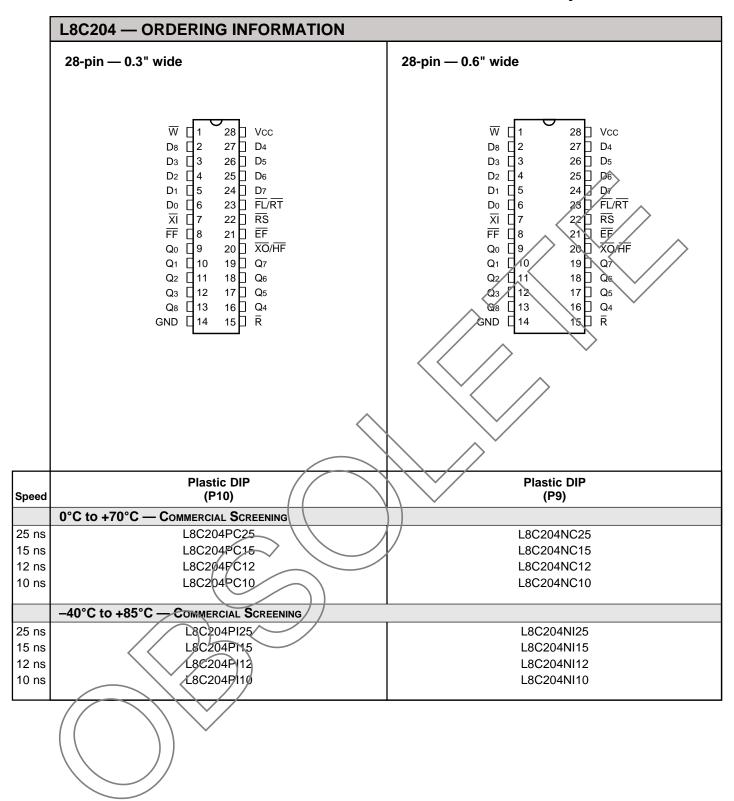








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